

## NDS352AP

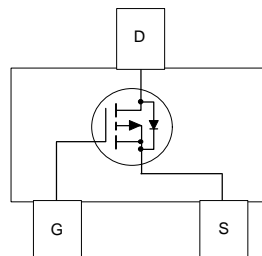
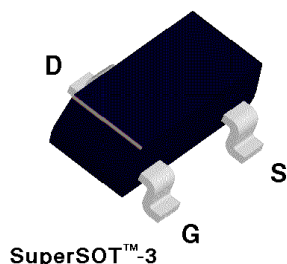
### P-Channel Logic Level Enhancement Mode Field Effect Transistor

#### General Description

These P -Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management, portable electronics, and other battery powered circuits where fast high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

#### Features

- -0.9 A, -30 V.  $R_{DS(ON)} = 0.5 \Omega$  @  $V_{GS} = -4.5$  V  
 $R_{DS(ON)} = 0.3 \Omega$  @  $V_{GS} = -10$  V.
- Industry standard outline SOT-23 surface mount package using proprietary SuperSOT™-3 design for superior thermal and electrical capabilities.
- High density cell design for extremely low  $R_{DS(ON)}$ .
- Exceptional on-resistance and maximum DC current capability.



#### Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	NDS352AP	Units
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-Source Voltage - Continuous	$\pm 20$	V
$I_D$	Maximum Drain Current - Continuous (Note 1a)	$\pm 0.9$	A
	- Pulsed	$\pm 10$	
$P_D$	Maximum Power Dissipation (Note 1a) (Note 1b)	0.5	W
		0.46	
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$
<b>THERMAL CHARACTERISTICS</b>			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	250	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	75	$^\circ\text{C/W}$

**Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}$ , $I_D = -250\text{ }\mu\text{A}$	-30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -24\text{ V}$ , $V_{GS} = 0\text{ V}$			-1	$\mu\text{A}$
		$T_J = 125^\circ\text{C}$			-10	$\mu\text{A}$
$I_{GSSF}$	Gate - Body Leakage, Forward	$V_{GS} = 20\text{ V}$ , $V_{DS} = 0\text{ V}$			100	nA
$I_{GSSR}$	Gate - Body Leakage, Reverse	$V_{GS} = -20\text{ V}$ , $V_{DS} = 0\text{ V}$			-100	nA
ON CHARACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = -250\text{ }\mu\text{A}$	-0.8	-1.7	-2.5	V
		$T_J = 125^\circ\text{C}$	-0.5	-1.4	-2.2	
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = -4.5\text{ V}$ , $I_D = -0.9\text{ A}$		0.45	0.5	$\Omega$
		$T_J = 125^\circ\text{C}$		0.65	0.7	
		$V_{GS} = -10\text{ V}$ , $I_D = -1\text{ A}$		0.25	0.3	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = -4.5\text{ V}$ , $V_{DS} = -5\text{ V}$	-2			A
$g_{FS}$	Forward Transconductance	$V_{DS} = -5\text{ V}$ , $I_D = -0.9\text{ A}$		1.9		S
DYNAMIC CHARACTERISTICS						
$C_{iss}$	Input Capacitance	$V_{DS} = -15\text{ V}$ , $V_{GS} = 0\text{ V}$ , $f = 1.0\text{ MHz}$		135		pF
$C_{oss}$	Output Capacitance			88		pF
$C_{rss}$	Reverse Transfer Capacitance			40		pF
SWITCHING CHARACTERISTICS (Note 2)						
$t_{d(on)}$	Turn - On Delay Time	$V_{DD} = -6\text{ V}$ , $I_D = -1\text{ A}$ , $V_{GS} = -4.5\text{ V}$ , $R_{GEN} = 6\text{ }\Omega$		5	10	ns
$t_r$	Turn - On Rise Time			17	30	ns
$t_{d(off)}$	Turn - Off Delay Time			35	70	ns
$t_f$	Turn - Off Fall Time			30	60	ns
$t_{d(on)}$	Turn - On Delay Time	$V_{DD} = -10\text{ V}$ , $I_D = -1\text{ A}$ , $V_{GS} = -10\text{ V}$ , $R_{GEN} = 50\text{ }\Omega$		8	15	ns
$t_r$	Turn - On Rise Time			16	30	ns
$t_{d(off)}$	Turn - Off Delay Time			35	90	ns
$t_f$	Turn - Off Fall Time			30	90	ns
$Q_g$	Total Gate Charge	$V_{DS} = -10\text{ V}$ , $I_D = -0.9\text{ A}$ , $V_{GS} = -4.5\text{ V}$		2	3	nC
$Q_{gs}$	Gate-Source Charge			0.5		nC
$Q_{gd}$	Gate-Drain Charge			1		nC

Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

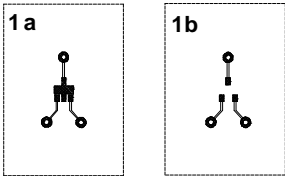
Symbol	Parameter	Conditions	Min	Typ	Max	Units
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I <sub>S</sub>	Maximum Continuous Source Current				-0.42	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				-10	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -0.42 (Note 2)		-0.8	-1.2	V

- Notes:
1. R<sub>θJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>θJC</sub> is guaranteed by design while R<sub>θCA</sub> is determined by the user's board design.

$$P_D(t) = \frac{T_J - T_A}{R_{\theta JA}(t)} = \frac{T_J - T_A}{R_{\theta JC} + R_{\theta CA}(t)} = I_D^2(t) \times R_{DS(ON)@T_J}$$

Typical R<sub>θJA</sub> using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 250°C/W when mounted on a 0.02 in<sup>2</sup> pad of 2oz copper.
- b. 270°C/W when mounted on a 0.001 in<sup>2</sup> pad of 2oz copper.



Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2.0%.

## Typical Electrical Characteristics

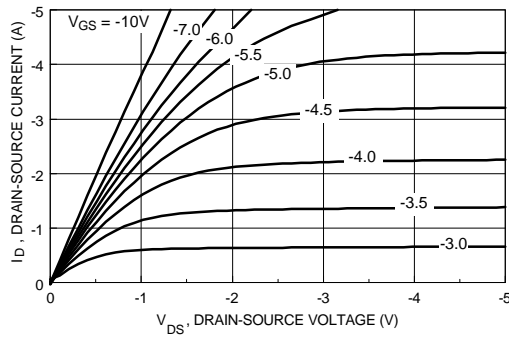


Figure 1. On-Region Characteristics.

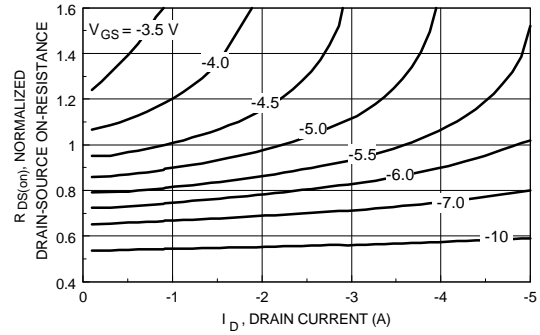


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

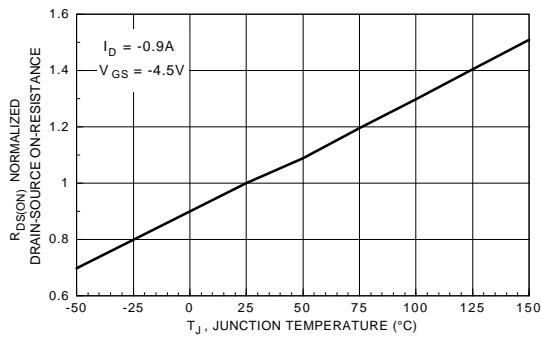


Figure 3. On-Resistance Variation with Temperature.

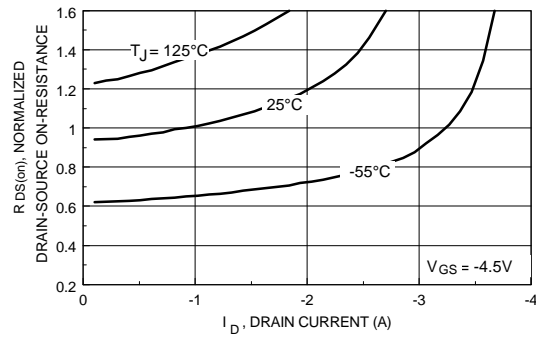


Figure 4. On-Resistance Variation with Drain Current and Temperature.

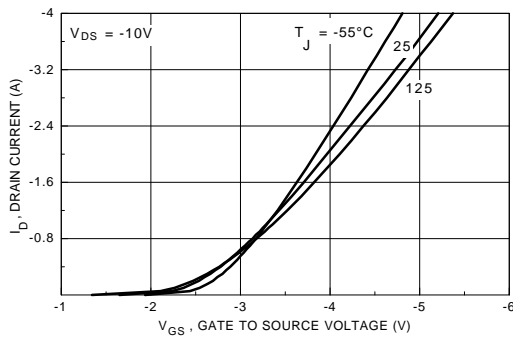


Figure 5. Transfer Characteristics.

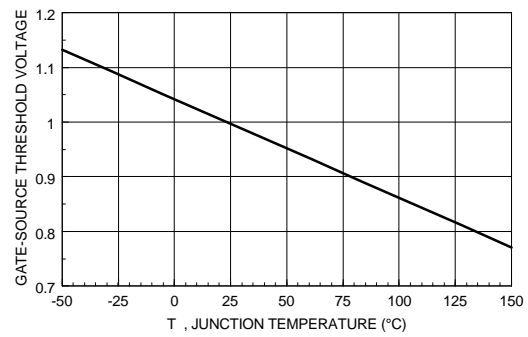
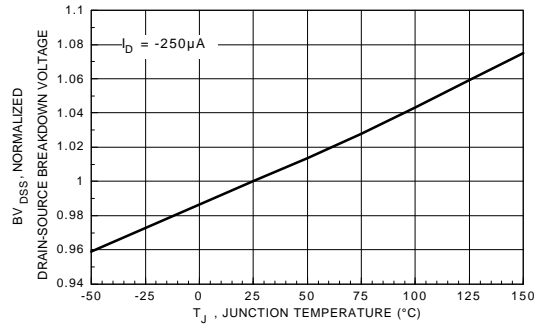
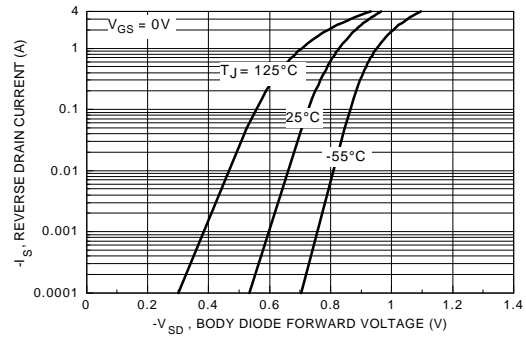


Figure 6. Gate Threshold Variation with Temperature.

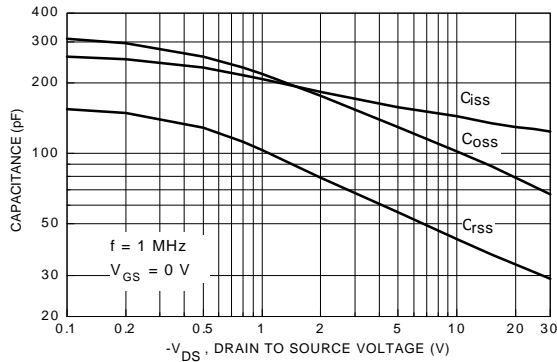
## Typical Electrical Characteristics (continued)



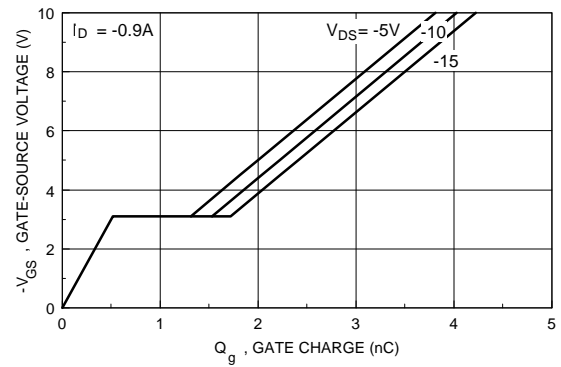
**Figure 7. Breakdown Voltage Variation with Temperature.**



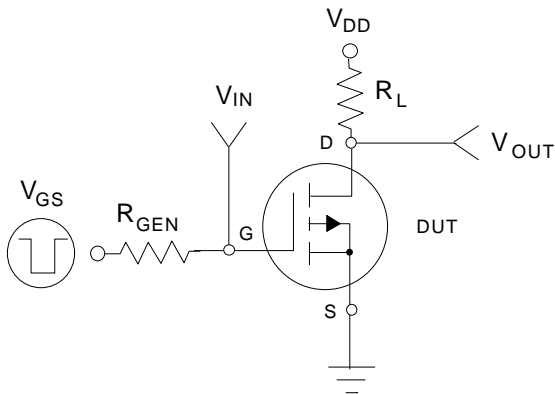
**Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature.**



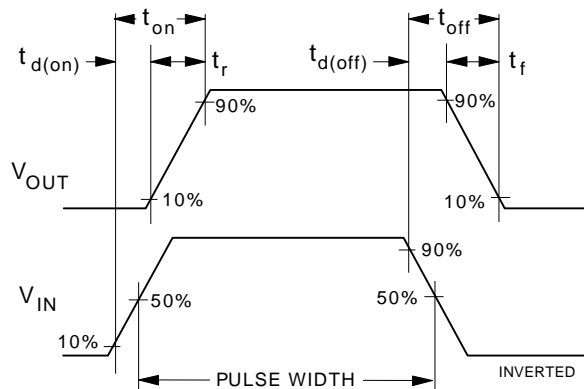
**Figure 9. Capacitance Characteristics.**



**Figure 10. Gate Charge Characteristics.**

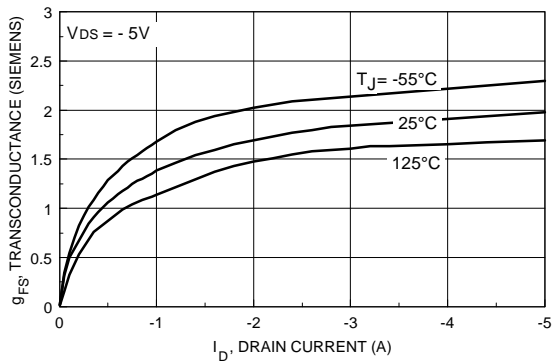


**Figure 11. Switching Test Circuit.**

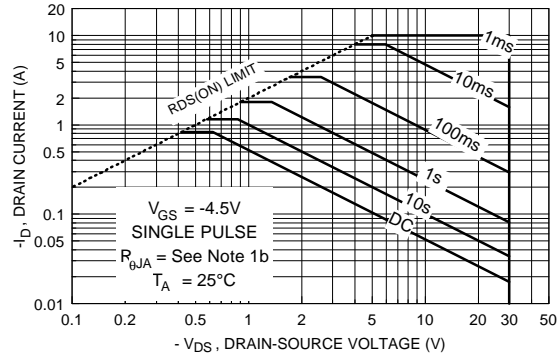


**Figure 12. Switching Waveforms.**

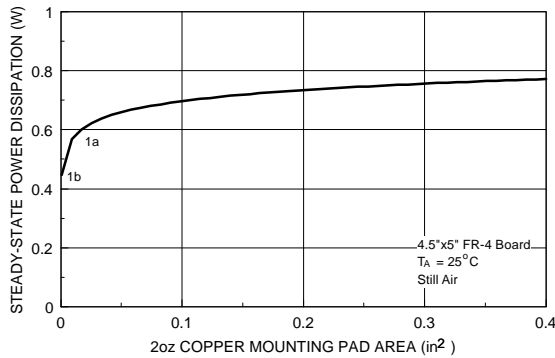
## Typical Electrical Characteristics (continued)



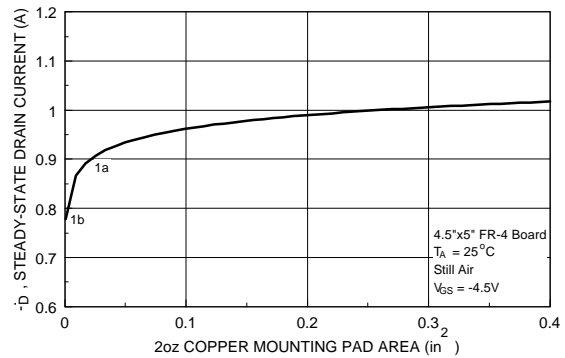
**Figure 13. Transconductance Variation with Drain Current and Temperature.**



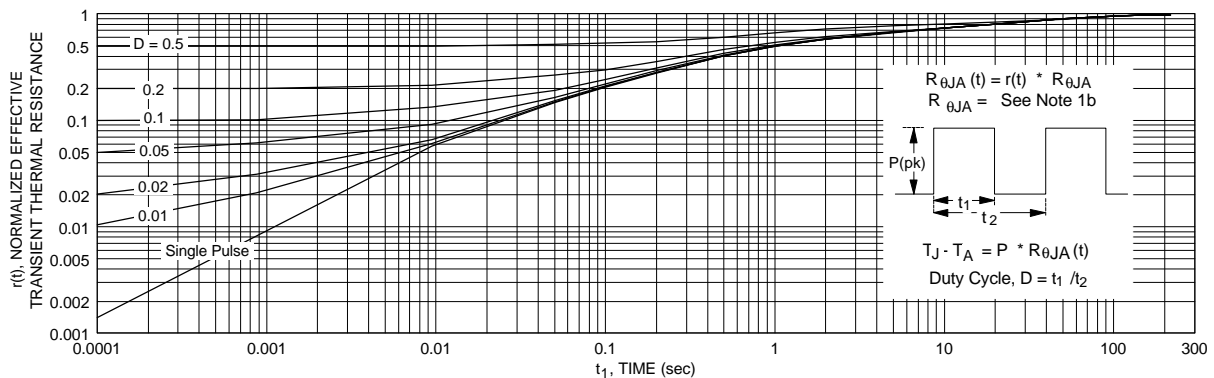
**Figure 14. Maximum Safe Operating Area.**



**Figure 15. SuperSOT™-3 Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.**



**Figure 16. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.**



**Figure 17. Transient Thermal Response Curve.**

Note : Characterization performed using the conditions described in note 1b. Transient thermal response will change depending on the circuit board design.

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